

N-channel TrenchMOS intermediate level FET Rev. 1 — 12 July 2011

Product data sheet

1. **Product profile**

1.1 General description

Intermediate level gate drive N-channel enhancement mode Field-Effect Transistor (FET) in a plastic package using advanced TrenchMOS technology. This product has been designed and qualified to the appropriate AEC Q101 standard for use in high performance automotive applications.

1.2 Features and benefits

- AEC Q101 compliant
- Suitable for standard and logic level gate drive sources

1.3 Applications

- 12 V Automotive systems
- Electric and electro-hydraulic power steering
- Motors, lamps and solenoid control

1.4 Quick reference data

Table 1 Quick reference data

- Suitable for thermally demanding environments due to 175 °C rating
- Start-Stop micro-hybrid applications
- Transmission control
- Ultra high performance power switching

Table 1.	Quick reference data						
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	-	40	V
I _D	drain current	V _{GS} = 10 V; T _{mb} = 25 °C; see <u>Figure 1</u>	<u>[1]</u>	-	-	90	A
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	-	128	W
Static cha	racteristics						
R _{DSon}	drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 15 \text{ A};$ $T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 11}{100000000000000000000000000000000$		-	5.2	6.2	mΩ



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Table 1.	Quick reference data	continued				
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
Avalanch	e ruggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ \begin{split} I_D &= 90 \text{ A}; V_{sup} \leq 40 \text{ V}; \\ R_{GS} &= 50 \Omega; V_{GS} = 10 \text{ V}; \\ T_{j(\text{init})} &= 25 ^\circ\text{C}; \text{ unclamped} \end{split} $	-	-	113	mJ
Dynamic	characteristics					
Q _{GD}	gate-drain charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V};$ $V_{GS} = 10 \text{ V}; \text{ see } \underline{Figure 13};$ see $\underline{Figure 14}$	-	20	-	nC

[1] Continuous current is limited by package.

2. Pinning information

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Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate		_
2	D	drain	mb	
3	S	source		
mb	D	mounting base; connected to drain		mbb076 S

SOT428 (DPAK)

3. Ordering information

Table 3. Ordering	information		
Type number	Package		
	Name	Description	Version
BUK626R2-40C	DPAK	plastic single-ended surface-mounted package (DPAK); 3 leads (one lead cropped)	SOT428

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4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions		Min	Max	Unit
V _{DS}	drain-source voltage	T _j ≥ 25 °C; T _j ≤ 175 °C		-	40	V
V _{GS}	gate-source voltage	DC	<u>[1]</u>	-16	16	V
		Pulsed	[2]	-20	20	V
I _D	drain current	T_{mb} = 25 °C; V_{GS} = 10 V; see <u>Figure 1</u>	[3]	-	90	А
		T_{mb} = 100 °C; V_{GS} = 10 V; see <u>Figure 1</u>		-	70	А
I _{DM}	peak drain current	T _{mb} = 25 °C; pulsed; t _p ≤ 10 μs; see <u>Figure 3</u>		-	397	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; see <u>Figure 2</u>		-	128	W
T _{stg}	storage temperature			-55	175	°C
Tj	junction temperature			-55	175	°C
Source-drain	diode					
I _S	source current	T _{mb} = 25 °C	[3]	-	90	А
I _{SM}	peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$		-	397	А
Avalanche rug	ggedness					
E _{DS(AL)S}	non-repetitive drain-source avalanche energy	$ I_D = 90 \text{ A}; \text{V}_{\text{sup}} \leq 40 \text{ V}; \text{R}_{\text{GS}} = 50 \Omega; \\ \text{V}_{\text{GS}} = 10 \text{ V}; \text{T}_{\text{j(init)}} = 25 ^{\circ}\text{C}; \text{ unclamped} $		-	113	mJ
E _{DS(AL)R}	repetitive drain-source avalanche energy		<u>[4][5][6]</u>	-	-	J

[1] -16V accumulated duration not to exceed 168 hrs.

[2] Accumulated pulse duration not to exceed 5mins.

[3] Continuous current is limited by package.

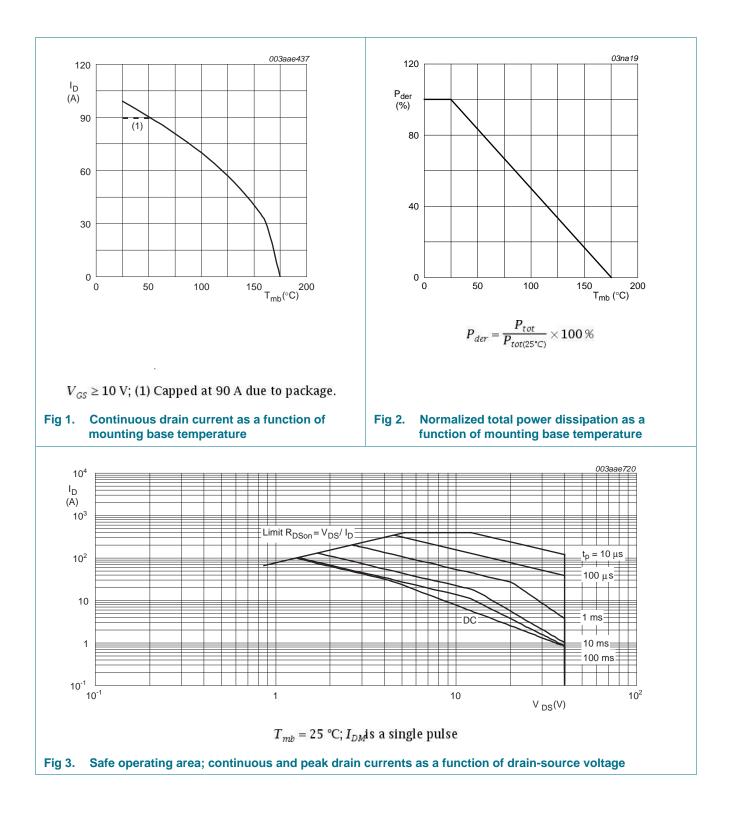
[4] Single-pulse avalanche rating limited by maximum junction temperature of 175 °C.

[5] Repetitive avalanche rating limited by an average junction temperature of 170 °C.

[6] Refer to application note AN10273 for further information.

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5. Thermal characteristics

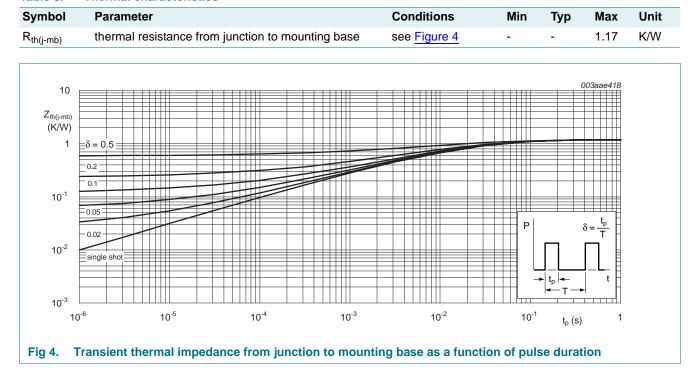


Table 5. Thermal characteristics

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6. Characteristics

Table 6.	Characteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static cha	racteristics					
V _{(BR)DSS}	drain-source breakdown voltage	$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = 25 \ ^\circ\text{C}$	40	-	-	V
		$I_D = 250 \ \mu\text{A}; \ V_{GS} = 0 \ V; \ T_j = -55 \ ^\circ\text{C}$	36	-	-	V
V _{GS(th)}	gate-source threshold voltage	$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 25 \text{ °C};$ see <u>Figure 9</u> ; see <u>Figure 10</u>	1.8	2.3	2.8	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = -55 \text{ °C};$ see Figure 9	-	-	3.3	V
		$I_D = 1 \text{ mA}; V_{DS} = V_{GS}; T_j = 175 \text{ °C};$ see <u>Figure 9</u>	0.8	-	-	V
I _{DSS}	drain leakage current	V_{DS} = 40 V; V_{GS} = 0 V; T_j = 175 °C	-	-	500	μA
		V_{DS} = 40 V; V_{GS} = 0 V; T_j = 25 °C	-	0.02	1	μA
I _{GSS}	gate leakage current	$V_{GS} = 20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
		$V_{GS} = -20 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 ^{\circ}\text{C}$	-	2	100	nA
R _{DSon}		V _{GS} = 10 V; I _D = 15 A; T _j = 25 °C; see <u>Figure 11</u>	-	5.2	6.2	mΩ
		V_{GS} = 5 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 11</u>	-	7	8.8	mΩ
		V_{GS} = 4.5 V; I_D = 15 A; T_j = 25 °C; see <u>Figure 11</u>	-	8	10.7	mΩ
		V_{GS} = 10 V; I_D = 15 A; T_j = 175 °C; see <u>Figure 12</u> ; see <u>Figure 11</u>	-	-	13	mΩ
Dynamic	characteristics					
Q _{G(tot)}	total gate charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$ see Figure 13; see Figure 14	-	67	-	nC
		$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 5 \text{ V};$ see Figure 13; see Figure 14	-	39	-	nC
Q _{GS}	gate-source charge	$I_D = 25 \text{ A}; V_{DS} = 32 \text{ V}; V_{GS} = 10 \text{ V};$	-	11	-	nC
Q _{GD}	gate-drain charge	see Figure 13; see Figure 14	-	20	-	nC
C _{iss}	input capacitance	$V_{GS} = 0 V; V_{DS} = 25 V; f = 1 MHz;$	-	2790	3720	pF
C _{oss}	output capacitance	$T_j = 25 \text{ °C}; \text{ see } \frac{\text{Figure } 15}{1000}$	-	380	456	pF
C _{rss}	reverse transfer capacitance		-	275	377	pF
t _{d(on)}	turn-on delay time	$V_{DS} = 30 \text{ V}; \text{ R}_{L} = 1.2 \Omega; V_{GS} = 10 \text{ V};$	-	16.7	-	ns
t _r	rise time	$R_{G(ext)} = 10 \ \Omega$	-	48.6	-	ns
t _{d(off)}	turn-off delay time		-	124	-	ns
t _f	fall time		-	17	-	ns
L _D	internal drain inductance	from upper edge of drain mounting base to centre of die ; $T_j = 25 \text{ °C}$	-	3.5	-	nH
L _S	internal source inductance	from source lead to source bond pad ; $T_j = 25 \ ^{\circ}C$	-	7.5	-	nH

Symbol

Source-drain diode

BUK626R2-40C

Unit

Max

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Тур

Min

0	source-drain voltage	$I_S = 25 \text{ A}; V_{GS} = 0 \text{ V}$ see <u>Figure 16</u>	, · j,			1.2	
	reverse recovery time	I _S = 20 A; dI _S /dt = -		-	43	-	ns
	recovered charge	$V_{\rm GS} = 0 \text{ V}; V_{\rm DS} = 28$	5 V	-	56	-	nC
	00)3aae721				003aae723	
100 I _D	$V_{GS}(V) = 10/6.0/5.0$	10					
(A)		(S)					
80 -		3	0			+	
60 -		4.0	60				
40							
40		3.8	0				
20 -		3.6	20				
20		3.4					
0		3.2	0				
				40	60	80 10	0
0	0.25 0.5 0.75 _V	/ _{DS} (V) ¹	0 20	40	00	⁸⁰ I _D (A) ¹⁰	-
0		ν _{DS} (V) ¹					-
0	0.25 0.5 0.75 $_{\rm V}$ $T_j = 25$ °C; $t_p = 300 \mu { m s}$	/ _{DS} (V) ¹		$= 25 ^{\circ}\text{C}; V_{L}$			-
g 5. Oı	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur	rent as a Fig 6.	T _j Forward tra	= 25 °C; V_L	$\sigma_S = 15$ N	/	
g 5. Oı	$T_j = 25 \text{ °C}; t_p = 300 \ \mu \text{s}$	rent as a Fig 6.	T_{j}	= 25 °C; V_L	$\sigma_S = 15$ N	/	
g 5. Oı	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	rrent as a Fig 6.	T _j Forward tra	= 25 °C; V_L	$\sigma_S = 15$ N	/	
g 5. Or ful ²⁵ R _{DSon}	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values	T _j Forward tra drain currer	= 25 °C; V_L	$\sigma_S = 15$ N	/ s a functio	
g 5. O t ful ²⁵	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward tra drain currer	= 25 °C; V_L	$\sigma_S = 15$ N	/ s a functio	
g 5. Ot ful ²⁵ R _{DSon} (mΩ)	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward tra drain currer	= 25 °C; V_L	$\sigma_S = 15$ N	/ s a functio	
g 5. Ot ful ²⁵ R _{DSon} (mΩ)	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward tra drain currer	= 25 °C; V _L ansconduct nt; typical v	_S = 15 V ance as alues		
g 5. Ot fu ²⁵ R _{DSon} (mΩ) 20	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward tra drain currer	= 25 °C; V_L	_S = 15 V ance as alues	/ s a functio	
g 5. Ot fu ²⁵ R _{DSon} (mΩ) 20	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward tra drain currer	= 25 °C; V _L ansconduct nt; typical v	_S = 15 V ance as alues		
g 5. Ot ful 25 R _{DSon} (mΩ) 20 15	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	Tj Forward tradrain currer 60 45 30	= 25 °C; V _L ansconduct nt; typical v	_S = 15 V ance as alues		
g 5. Ot ful 25 R _{DSon} (mΩ) 20 15	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward tra drain currer	= 25 °C; V _L ansconduct nt; typical v	_S = 15 V ance as alues		
g 5. Or fun 25 R _{DSon} (mΩ) 20 15	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	Tj Forward tradrain currer 60 45 30	= 25 °C; V _L ansconduct nt; typical v	_S = 15 V ance as alues		
g 5. Or fu 25 R _{DSon} (mΩ) 20 15 10 5 0	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. 33aae727 Image: style	<i>T</i> _j Forward tra drain curren	= 25 °C; V_L insconduct nt; typical v $T_j = 17$	os = 15 V ance as values	003aae722	
g 5. Or fun ²⁵ ^R _{DSon} (mΩ) 20 15 10 5	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. Stypical values 132aae727 Image: Constraint of the second seco	T _j Forward traddrain curren 60	= 25 °C; V _L ansconduct nt; typical v	os = 15 V ance as values		
g 5. Or fu 25 R _{DSon} (mΩ) 20 15 10 5 0	$T_j = 25$ °C; $t_p = 300 \ \mu s$ utput characteristics: drain cur inction of drain-source voltage;	Fig 6. 33aae727 Image: style	<i>T</i> _j Forward trad drain curren	= 25 °C; V_L insconduct nt; typical v $T_j = 17$	$p_S = 15$ M ance as values	003aae722	

Conditions

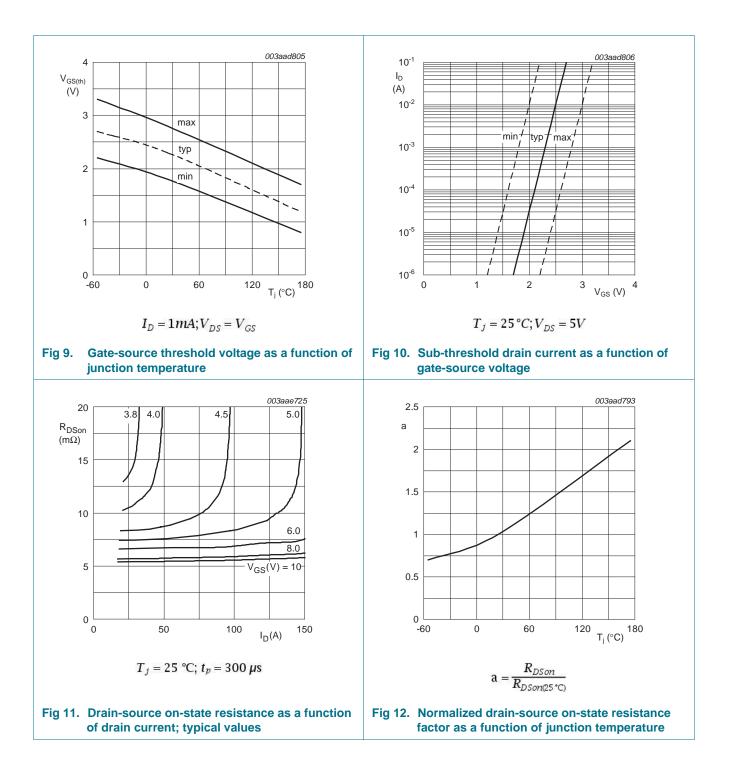
Table 6. Characteristics con	ntinued
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Parameter

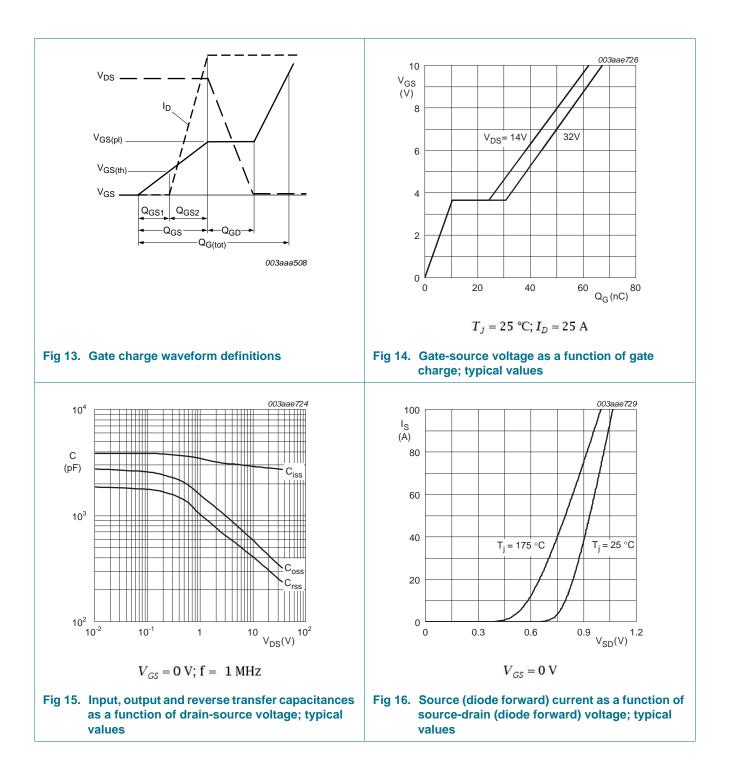
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7. Package outline

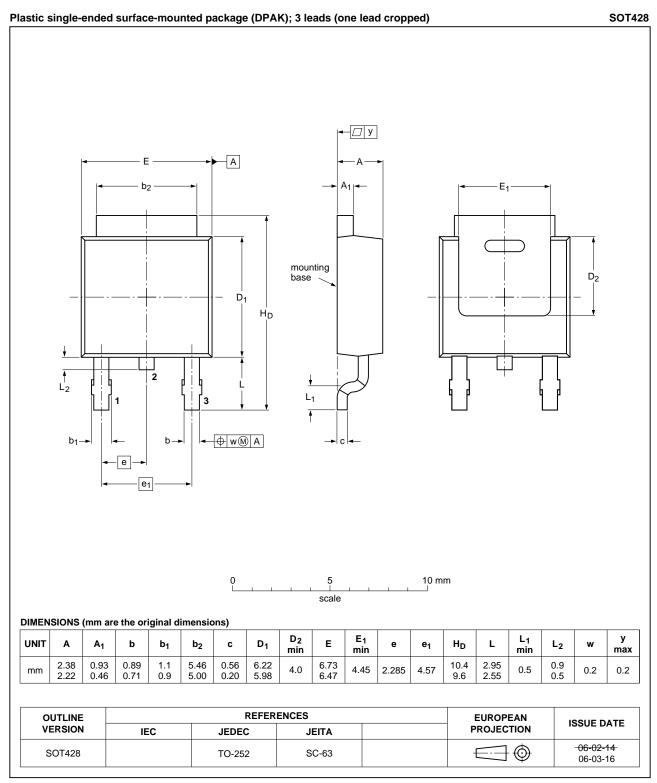


Fig 17. Package outline SOT428 (DPAK)

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8. Revision history

Table 7. Revision h	Revision history					
Document ID	Release date	Data sheet status	Change notice	Supersedes		
BUK626R2-40C v.1	20110712	Product data sheet	-	-		

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9. Legal information

9.1 Data sheet status

Document status [1] [2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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